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Remarks:

This application was filed on 30-09-2010 as a divisional application to the application mentioned under INID code 62.

(54) **A probe for testing electrical properties of a test sample**

(57) The present invention relates to a probe (502) for testing electrical properties of test samples (508). The probe may comprise a body (504) having a probe arm (506) defining a proximal and an opposite distal end, the probe arm extending from the body at the proximal end of the probe arm, a first axis defined by the proximal and the distal end. Further, the probe arm may define a geometry allowing flexible movement of the probe arm along the first axis and along a second axis perpendicularly to the first axis and along a third axis orthogonal to a plane defined by the first axis and second axis.

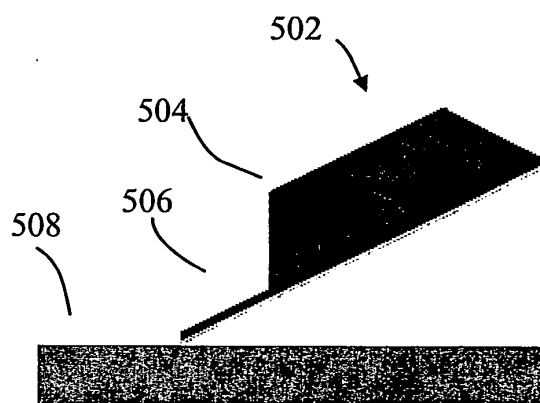


Fig. 2